## Applicant(s)/Patent Under Application/Control No. Reexamination 10/553,968 ODAKA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1742 John P. Sheehan **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY US-5,690,752 11-1997 Yamamoto et al. 148/302 Α 148/104 US-5,595,608 A 01-1997 Takebuchi et al. В US-C UŞ-D US-Ε US-F US-G Н US-US-US-J US-Κ US-US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S

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